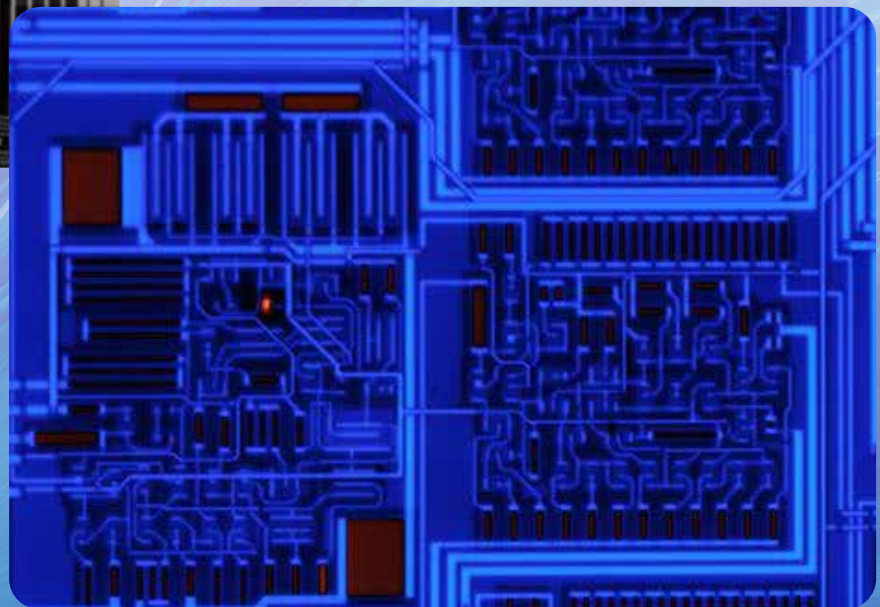
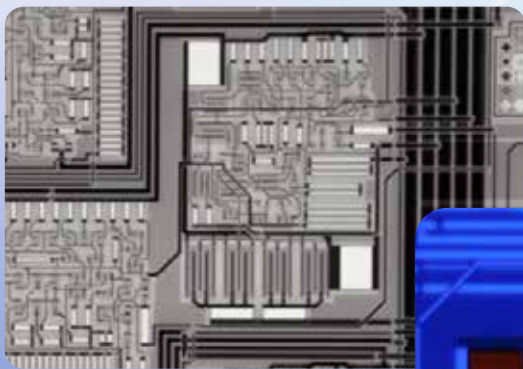


SEMI-CHECK

Advanced NDT For Semi-Conductors

IR-NDT TECHNOLOGY



Turn-Key Solution for Semi-Conductor Testing

- ✓ Semi-Conductor Failure Analysis
- ✓ Lock-in Thermography
- ✓ Functional Circuit Analysis (Power Dissipation, Shorts, etc.)
- ✓ Forensic Research

Discover the next generation of semi-conductor test equipment - surprisingly affordable.

The MoviTHERM Semi-Check system is an affordable Lock-in Thermography system with built in 2-quadrant power supply. The power supply allows for separate current and voltage modulation using square wave, sinusoidal and arbitrary waveforms. The combination of Lock-in Thermography with a high-end cooled thermal camera makes it possible to detect thermal variations in the **micro Kelvin range**.

A special Lock-in online mode allows for virtually indefinite measurement periods for extremely low signals.

Supported Thermal Cameras

The Semi-Check system supports thermal cameras from FLIR Systems, Inc. From long wave infrared (LWIR 8-14 μ m) uncooled micro-bolometers, to scientific, cooled mid-wave infrared (MWIR 3-5 μ m). Microscopic lens attachments are available for these cameras for spatial resolutions down to 4 μ m/pixel.

Microscopic Stand

The microscopic stand with manual Z-axis allows for rapid change-over from larger parts, such as entire circuit boards or large wafers to microscopic inspections. The base plate has a standard 1" x 1" hole pattern to mount micrometer stages, probe stations or other accessories. The stand is compatible with all support FLIR cameras.

Automated Testing

The system has built-in, programmable digital I/O for automated testing in a production line. The testing sequence can be programming using the built in Visual Basic Script Engine.

